## Application/Control No. Applicant(s)/Patent Under Reexamination 10/683,947 MEEK ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Winnie Yip 3636 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY US-3,664,513 05-1972 Atwater, Wayne G. Α 211/134 US-В US-С D US-US-Ε F US-US-G US-Н US-1 US-US-Κ US-L US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) υ ٧ W

<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.